

**Search Notes**

Application/Control No.

10/821,169

Examiner

Hanh V. Tran

Applicant(s)/Patent under  
Reexamination

SHIN ET AL.

Art Unit

3637

**SEARCHED**

Class	Subclass	Date	Examiner
312	405 244	3/20/2006	HVT
	348.6		
16	413 436		
	444		
	Dig40		
16	Dig41	3/20/2006	HVT
All	Above	8/30/2006	HVT
	Updated		
All	Updated	3/19/2007	HVT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search using various key words	3/20/2006	HVT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner